







THS4031, THS4032 SLOS224K - JULY 1999 - REVISED MAY 2024

THS403x 100MHz, Low-Noise, High-Speed Amplifiers

1 Features

Texas

- Ultra-low 1.2nV/√Hz voltage noise
- High speed:
 - 100MHz bandwidth [G = 2 (-1), -3dB]
 - 100V/µs slew rate

Instruments

- Very low distortion
 - THD = -81dBc (f = 1MHz, R_L = 150 Ω)
- THD = -96dBc (f = 1MHz, R_L = 1k Ω)
- Low 0.3mV (typical) input offset voltage
- 200mA output current drive (typical)
- Typical operation from ±4.5V to ±16V
- Offset nulling pins on the THS4031

2 Applications

- Low-noise, wide-band amplifier for industrial applications
- Voltage-controlled oscillators
- Active filters
- Video amplifiers
- Cable drivers
- Ultrasound scanner
- Vector signal transceiver (VST)
- Data acquisition (DAQ)

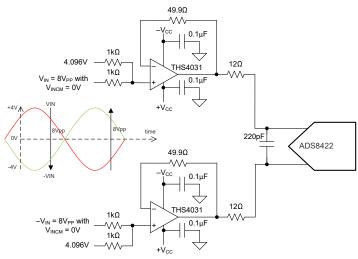
3 Description

The THS4031 and THS4032 (THS403x) are ultra-low voltage noise, high-speed voltage feedback amplifiers that are an excellent choice for applications requiring low voltage noise, including communications and imaging. The single-amplifier THS4031 and the dualamplifier THS4032 offer very good ac performance with 100MHz bandwidth (G = 2), 100V/µs slew rate, and 70ns settling time (0.1%). The THS403x are unity-gain stable with 120MHz bandwidth. These amplifiers have a high drive capability of 200mA and draw only 7.5mA supply current per channel. With -96dBc of total harmonic distortion (THD) at f = 1MHz and a very low noise of $1.2 \text{nV}/\sqrt{\text{Hz}}$, the THS403x are designed for applications requiring low distortion and low noise such as buffering analog-todigital converters.

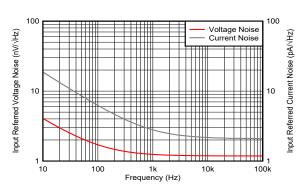
Package Information

PART NUMBER	AMPLIFIERS	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾			
THS4031 One	One	D (SOIC, 8)	4.9mm × 6mm			
	Offe	DGN (HVSSOP, 8)	3.0mm × 4.9mm			
THS4032	032 Two	D (SOIC, 8)	4.9mm × 6mm			
1H54032		DGN (HVSSOP, 8)	3.0mm × 4.9mm			

- For more information, see Section 10. (1)
- The package size (length × width) is a nominal value and includes pins, where applicable.



High-Performance, Low-Noise Driver for 16-Bit SAR ADCs



Voltage and Current Noise vs Frequency



Table of Contents

1 Features1	6.2 Functional Block Diagrams	. 26
2 Applications1	6.3 Feature Description	
3 Description1	6.4 Device Functional Modes	
4 Pin Configuration and Functions3	7 Application and Implementation	. 28
5 Specifications 4	7.1 Application Information	. 28
5.1 Absolute Maximum Ratings4	7.2 Typical Application	. 30
5.2 ESD Ratings4	7.3 Power Supply Recommendations	33
5.3 Recommended Operating Conditions4	7.4 Layout	
5.4 Thermal Information - THS40315	8 Device and Documentation Support	
5.5 Thermal Information - THS40325	8.1 Documentation Support	. 36
5.6 Electrical Characteristics - THS4031, R _L = 150Ω6	8.2 Receiving Notification of Documentation Updates	36
5.7 Electrical Characteristics - THS4031, R _L = 1kΩ7	8.3 Support Resources	. 36
5.8 Electrical Characteristics - THS4032, R _L = 150Ω9	8.4 Trademarks	
5.9 Electrical Characteristics - THS4032, R _L = 1kΩ 10	8.5 Electrostatic Discharge Caution	36
5.10 Typical Characteristics - THS403112	8.6 Glossary	36
5.11 Typical Characteristics - THS403218	9 Revision History	
6 Detailed Description26	10 Mechanical, Packaging, and Orderable	
6.1 Overview26	Information	. 39



4 Pin Configuration and Functions

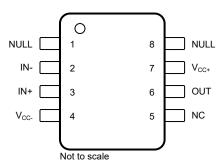


Figure 4-1. THS4031: D Package, 8-Pin SOIC, or DGN Package, 8-pin HVSSOP (Top View)

Table 4-1. Pin Functions: THS4031

PIN		TYPE	DESCRIPTION		
NAME	NO.	ITPE	DESCRIPTION		
IN-	2	Input	Inverting input		
IN+	3	Input	Non-inverting input		
NC	5	_	No connection		
NULL	1, 8	Input	Voltage offset adjust		
OUT	6	Output	Output of amplifier		
V _{CC} -	4	_	Negative power supply		
V _{CC+}	7	_	Positive power supply		

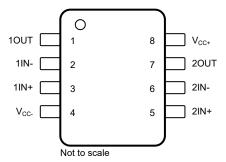


Figure 4-2. THS4032: D Package, 8-Pin SOIC, or DGN Package, 8-pin HVSSOP (Top View)

Table 4-2. Pin Functions: THS4032

	PIN	TYPE	DESCRIPTION
NAME	NO.	ITPE	DESCRIPTION
1IN-	2	Input	Channel 1 inverting input
1IN+	3	Input	Channel 1 non-inverting input
10UT	1	Output	Channel 1 output
2IN-	6	Input	Channel 2 inverting input
2IN+	5	Input	Channel 2 non-inverting input
2OUT	7	Output	Channel 2 output
V _{CC} -	4	_	Negative power supply
V _{CC+}	8	_	Positive power supply



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC-} to V _{CC+}	Supply voltage			33	V
VI	Input voltage			±V _{CC}	V
Io	Output current ⁽²⁾			240	mA
V _{IO}	Differential input voltage			±1.5	V
I _{IN}	Continuous input current			10	mA
_	Operating free-air temperature	C-suffix	0	70	°C
T _A		I-suffix	-40	85	C
		Any condition		150	
T_J	Junction temperature	Maximum junction temperature, continuous operation, long term reliability ⁽³⁾		130	°C
	Lead temperature 1,6 mm (1/16 inch) for	rom case for 10 seconds		300	°C
T _{stg}	Storage temperature		-65	150	°C

- (1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.
- (2) When continuously operating at any output current, do not exceed the maximum junction temperature. Keep the output current less than the absolute maximum rating regardless of time interval.
- (3) The maximum junction temperature for continuous operation is limited by package constraints. Operation greater than this temperature can result in reduced reliability, lifetime of the device, or both.

5.2 ESD Ratings

			VALUE	UNIT
\/	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins ⁽¹⁾	±1000	V
V _(ESD)	Liectiostatic discharge	Charged device model (CDM), per JEDEC specification JS-002 ⁽²⁾	±1000	V

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

	<u> </u>	,				
			MIN	NOM	MAX	UNIT
V _{CC} Supp	Supply voltage	Dual-supply	±4.5	±15	±16	\/
	Supply voltage	Single-supply	9	30	32	V
T _A Ope	Operating free-air temperature	C-suffix	0	25	70	°C
		I-suffix	-40	25	85	C

Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated



5.4 Thermal Information - THS4031

		THS		
THERMAL METRIC ⁽¹⁾		D (SOIC)		UNIT
		8 PINS	8 PINS	
R _{0JA}	Junction-to-ambient thermal resistance	124.5	60.7	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	65.0	87.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	72.2	33	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	13.6	7.9	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	71.3	32.9	°C/W
R ₀ JC(bot)	Junction-to-case (bottom) thermal resistance	N/A	17.2	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.5 Thermal Information - THS4032

		TH	THS4032			
	THERMAL METRIC ⁽¹⁾	D (SOIC)	DGN (HVSSOP)	UNIT		
		8 PINS	8 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	121.2	56.5	°C/W		
R _{0JC(top)}	Junction-to-case (top) thermal resistance	72.8	48.4	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	61.4	37.7	°C/W		
Ψ_{JT}	Junction-to-top characterization parameter	18.2	2.5	°C/W		
Ψ_{JB}	Junction-to-board characterization parameter	61	37.5	°C/W		
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	9.9	°C/W		

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



5.6 Electrical Characteristics - THS4031, R_L = 150 Ω

at $T_A = 25^{\circ}$ C, $V_{CC} = \pm 15$ V, and $R_L = 150\Omega$ (unless otherwise noted)

	PARAMETER	TEST CON	DITIONS	MIN	TYP	MAX	UNIT
DYNAM	IIC PERFORMANCE						
			V _{CC} = ±15V		100		
BW	Small-signal bandwidth (–3dB)	Gain = -1V/V or 2V/V	V _{CC} = ±5V		90		MHz
			V _{CC} = ±15V		9		
	Bandwidth for 0.1dB flatness	Gain = -1V/V or 2V/V	V _{CC} = ±5V		9		MHz
	- (4)		V _{CC} = ±15V, 20V step		100		
SR	Slew rate ⁽¹⁾	Gain = -1V/V	V _{CC} = ±5V, 5V step		80		V/µs
			V _{CC} = ±15V, 5V step		70		
		To 0.1%, gain = –1V/V	V _{CC} = ±5V, 2.5V step		55		
t _S	Settling time		V _{CC} = ±15V, 5V step		90		ns
		To 0.01%, gain = -1V/V	V _{CC} = ±5V, 2.5V step		80		
NOISE	AND DISTORTION PERFORMANCE						
THD	Total harmonic distortion	Gain = 2V/V, V _{CC} = ±5V or ±15V,	f = 1MHz V _{O(pp)} = 2V		-81		dBc
V _n	Input voltage noise	V _{CC} = ±5V or ±15V, f > 10kHz	,		1.2		nV/√Hz
I _n	Input current noise	V _{CC} = ±5V or ±15V, f > 10kHz			2.3		pA/√Hz
	D.W		V _{CC} = ±15V		0.015%		
	Differential gain error	Gain = 2V/V, 40 IRE modulation,	V _{CC} = ±5V		0.02%		
		NTSC and PAL, ±100 IRE ramp	V _{CC} = ±15V		0.025		•
	Differential phase error		V _{CC} = ±5V		0.03		0
DC PER	RFORMANCE						
			T _A = 25°C	93	100		
		$V_{CC} = \pm 15V, V_{O} = \pm 10V$	T _A = full range	92			
	Open-loop gain		T _A = 25°C	90	98		dB
		$V_{CC} = \pm 5V, V_{O} = \pm 2.5V$	T _A = full range	89			
			T _A = 25°C		0.3	2	
Vos	Input offset voltage	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range			3	mV
	Offset voltage drift	V _{CC} = ±5V or ±15V, T _A = full rang	e		2		μV/°C
			T _A = 25°C		9	20	
I _{IB}	Input bias current	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range			33	μA
			T _A = 25°C		30	250	
los	Input offset current	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range			400	nA
	Input offset current	V _{CC} = ±5V or ±15V, T _A = full rang	е		0.2		nA/°C
INPUT (CHARACTERISTICS						
.,	Common-mode input voltage	V _{CC} = ±15V		±13.5	±14.3		.,
V_{ICR}	range	V _{CC} = ±5V		±3.8	±4.3		V
		151111	T _A = 25°C	85	95		
		$V_{CC} = \pm 15V, V_{ICR} = \pm 12V$	T _A = full range	80			
CMRR	Common-mode rejection ratio	.5)/)/	T _A = 25°C	90	100		dB
		$V_{CC} = \pm 5V$, $V_{ICR} = \pm 2.5V$	T _A = full range	85			
R _i	Input resistance				2		МΩ
Ci	Input capacitance				1.5		pF
OUTPU	T CHARACTERISTICS	,					
	O. t	$V_{CC} = \pm 15V, R_{L} = 250\Omega$		±12	±12.9		
Vo	Output voltage swing	V _{CC} = ±5V		±3	±3.5		V
	0	D - 400	V _{CC} = ±15V	60	200		•
I _O	Output current ⁽²⁾	$R_L = 10\Omega$	V _{CC} = ±5V	50	160		mA
R _O	Output resistance	Open loop			5		Ω



5.6 Electrical Characteristics - THS4031, R_L = 150 Ω (continued)

at T_A = 25°C, V_{CC} = ±15V, and R_L = 150 Ω (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
POWER	SUPPLY						
V	Cumply voltage	Dual supply		±4.5		±16.5	V
V _{CC}	Supply voltage	Single supply		9		33	V
		V = 145V	T _A = 25°C		7.5	10	
	Cumply surrent (anch applifier)	V _{CC} = ±15V	T _A = full range			11	mA
Icc	Supply current (each amplifier)	\/ - +5\/	T _A = 25°C		6.5	9	mA
		$V_{CC} = \pm 5V$	T _A = full range			10.5	
PSRR	Dower cumply rejection ratio	Power-supply rejection ratio V_{CC} = ±5V or ±15V	T _A = 25°C	85	95		dB
PSRR	rower-supply rejection ratio		T _A = full range	80			uв

- (1) Slew rate is measured from an output level range of 25% to 75%.
- (2) Keep junction temperature less than the absolute maximum rating when the output is heavily loaded or shorted; see also Section 5.1.

5.7 Electrical Characteristics - THS4031, R_L = 1k Ω

at T_A = full range, V_{CC} = ±15V, and R_L = 1k Ω (unless otherwise noted)

	PARAMETER	TEST (CONDITIONS	MIN	TYP	MAX	UNIT
DYNAN	IIC PERFORMANCE						
	Unity gain bandwidth	V _{CC} = ±15V, closed loop		100 ⁽¹⁾	120		MHz
BW	Small-signal bandwidth	Gain = -1V/V or 2V/V	V _{CC} = ±15V		100		N 41 1-
BVV	(-3dB)	Gain = -10/0 or 20/0	V _{CC} = ±5V		90		MHz
	Bandwidth for 0.1dB flatness	Gain = -1V/V or 2V/V	V _{CC} = ±15V		9		MHz
	bandwidth for 0.10b flathess	Gain = -1V/V or 2V/V	V _{CC} = ±5V		9		IVITZ
	Full power bandwidth ⁽²⁾	V _{CC} = ±15V, V _{O(pp)} = 20V			1.6		MHz
	Full power bandwidth	$V_{CC} = \pm 5V, V_{O(pp)} = 5V$			5.1		IVITZ
SR	Slew rate			80 ⁽¹⁾	100		V/µs
	Settling time	To 0.1%, gain = -1V/V	V _{CC} = ±15V, 5V step		70		
t _S		10 0.170, gaili = -1777	V _{CC} = ±5V, 2.5V step		55		l
		To 0.01%, gain = -1V/V	V _{CC} = ±15V, 5V step		90		ns
		10 0.01%, gaiii – -10/V	V _{CC} = ±5V, 2.5V step		80		
NOISE	AND DISTORTION PERFORMANC	E	·				
THD	Total harmonic distortion	Gain =2V/V, V _{CC} = ±5V or ±1	5V, f = 1MHz V _{O(pp)} = 2V		-96		dBc
DC PEF	RFORMANCE						
		$V_{CC} = \pm 15V, V_{O} = \pm 10V$	T _A = 25°C	93	100		
	Open-loop gain	VCC - 113V, VO - 110V	T _A = full range	92			dB
	Open-100p gain	$V_{CC} = \pm 5V, V_{C} = \pm 2.5V$	T _A = 25°C	92	98		uБ
		VCC - 13V, VO - 12.3V	T _A = full range	91			
Vos	Input offset voltage	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = 25°C		0.3	2	mV
VOS	input onset voltage	VCC = 13V OI 113V	T _A = full range			3	IIIV
	Offset voltage drift	V_{CC} = ±5V or ±15V, T_A = full	range		2		μV/°C
I _{IB}	Input higs current	V _{CC} = ±5V or ±15V	T _A = 25°C		9	20	μA
чв	Input bias current	VCC = 13V OI 113V	T _A = full range			33	μΛ
loo	Input offset current	V _{CC} = ±5V or ±15V	T _A = 25°C		30	250	μA
Ios	input onset ourient	ACC - 724 OL 7.124	T _A = full range			400	μ.Λ.
	Input offset current drift	V_{CC} = ±5V or ±15V, T_A = full	range		0.2		nA/°C



5.7 Electrical Characteristics - THS4031, R_L = 1k Ω (continued)

at T_A = full range, V_{CC} = ±15V, and R_L = 1k Ω (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
INPUT C	HARACTERISTICS	'				<u> </u>	
	Common-mode input voltage	V _{CC} = ±15V		±13.5	±14.3		V
V _{ICR}	range	V _{CC} = ±5V		±3.8	±4.3		V
		V - 145V V - 140V	T _A = 25°C	85	95		
CMRR	Common made rejection retic	$V_{CC} = \pm 15V, V_{ICR} = \pm 12V$	T _A = full range	80			٩D
CIVIRR	Common-mode rejection ratio	$V_{CC} = \pm 5V$, $V_{ICR} = \pm 2.5V$	T _A = 25°C	90	100		dB
		V _{CC} = ±5V, V _{ICR} = ±2.5V	T _A = full range	85			
Ri	Input resistance				2		МΩ
Ci	Input capacitance				1.5		pF
OUTPUT	CHARACTERISTICS						
\/	Output voltage swing	V _{CC} = ±15V		±13	±13.6		V
Vo		V _{CC} = ±5V		±3.4	±3.8		
Ro	Output resistance	Open loop			5		Ω
POWER	SUPPLY						
\/	Cumply valtage energting range	Dual supply		±4.5		±16.5	V
V _{CC}	Supply voltage operating range	Single supply		9		33	V
	Supply current (each amplifier)	V _{CC} = ±15V	T _A = 25°C		7.5	10	
1			T _A = full range			11	m ^
I _{CC}		V _{CC} = ±5V	T _A = 25°C		6.5	9	mA
			T _A = full range			10	
DODD	Power-supply rejection ratio	V = 15V or 145V	T _A = 25°C	85	95		
PSRR		upply rejection ratio $V_{CC} = \pm 5V \text{ or } \pm 15V$		80			dB

⁽¹⁾ This minimum value is not tested.

Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated

⁽²⁾ Full power bandwidth = slew rate / $[\pi V_{O(P-P)}]$.



5.8 Electrical Characteristics - THS4032, $R_{\textrm{L}}$ = 150 Ω

at T_A = 25°C, V_{CC} = ±15V, and R_L = 150 Ω (unless otherwise noted)

	PARAMETER	TEST CO	ONDITIONS	MIN	TYP	MAX	UNIT
DYNAM	IC PERFORMANCE						
	Small-signal bandwidth (–3 dB)		V _{CC} = ±15V		100		
BW		Gain = -1V/V or 2V/V	V _{CC} = ±5V		90		MHz
	Bandwidth for 0.1dB flatness		V _{CC} = ±15V		50		
		Gain = -1V/V or 2V/V	V _{CC} = ±5V		45		MHz
	Slew rate ⁽¹⁾		V _{CC} = ±15V, 20V step		100		
SR		Gain = -1V/V	V _{CC} = ±5V, 5V step		80		V/µs
			V _{CC} = ±15V, 5V step		60		
		To 0.1%, Gain = -1V/V	V _{CC} = ±5V, 2.5V step		45		
t _S	Settling time	T 0 0 4 0 1 4 1 4 1 4 1	V _{CC} = ±15V, 5V step		90		ns
		To 0.01%, Gain = -1V/V	V _{CC} = ±5V, 2.5V step		80		
NOISE A	AND DISTORTION PERFORMANC	E					
THD	Total harmonic distortion	Gain = 2V/V, V _{CC} = ±5V or ±15	5V, f = 1MHz V _{O(pp)} = 2V		-72		dBc
V _n	Input voltage noise	V _{CC} = ±5V or ±15V, f > 10kHz	***		1.6		nV/√ Hz
l _n	Input current noise	V _{CC} = ±5V or ±15V, f > 10kHz			1.2		pA/√ Hz
	Differential gain error		V _{CC} = ±15V		0.015%		
		Gain = 2V/V, 40 IRE modulation,	V _{CC} = ±5V		0.02%		
	Differential phase error	NTSC and PAL, ±100 IRE ramp	V _{CC} = ±15V		0.025		0
			V _{CC} = ±5V		0.03		•
	Channel-to-channel crosstalk (THS4032 only)	V _{CC} = ±5V or ±15V, f = 1MHz			-61		dBc
DC PER	FORMANCE						
	Input offset voltage	V _{CC} = ±5V or ±15V	T _A = 25°C		0.5	2	
Vos			T _A = full range		-	3	mV
	Input offset current	V _{CC} = ±5V or ±15V	T _A = 25°C		30	250	
los			T _A = full range			400	nA
	Offset voltage drift	V_{CC} = ±5V or ±15V, T_A = full ra	ange		2		μV/°C
	Input offset current drift	V_{CC} = ±5V or ±15V, T_A = full ra	ange		0.2		nA/°C
INPUT C	CHARACTERISTICS				-		
	Common-mode input voltage	V _{CC} = ±15V		±13.5	±14		
V_{ICR}	range	V _{CC} = ±5V		±3.8	±4		V
			T _A = 25°C	85	95		
		$V_{CC} = \pm 15V$, $V_{ICR} = \pm 12V$	T _A = full range	80	-		
CMRR	Common-mode rejection ratio		T _A = 25°C	90	100		dB
		V_{CC} = ±5 V, V_{ICR} = ±2.5 V	T _A = full range	85			
Ri	Input resistance				2		ΜΩ
Ci	Input capacitance				1.5		pF
	T CHARACTERISTICS						<u> </u>
Vo		$V_{CC} = \pm 15V, R_{L} = 250\Omega$		±12	±12.9		
	Output voltage swing	V _{CC} = ±5V		±3	±3.5		V
			V _{CC} = ±15V	60	90		
lo	Output current ⁽²⁾	$R_L = 20\Omega$	$V_{CC} = \pm 5V$	50	70		mA
I _{SC}	Short-circuit current ⁽²⁾	V _{CC} = ±15V	1 00 -		150		mA
R ₀	Output resistance	Open loop			13		Ω



5.8 Electrical Characteristics - THS4032, R_L = 150 Ω (continued)

at T_A = 25°C, V_{CC} = ±15V, and R_L = 150 Ω (unless otherwise noted)

A	20 0, 100 = 101, 4114 11	10022 (0111000 011101111					
	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
POWER	SUPPLY					·	
V _{CC}	Cumply voltage energting range	Dual supply Single supply		±4.5		±16.5	V
	Supply voltage operating range			9		33	
I _{CC}	Supply current (each amplifier)	V _{CC} = ±15V	T _A = 25°C		8.5	10	
			T _A = full range			11	4
		V _{CC} = ±5V	T _A = 25°C		7.5	9	mA
			T _A = full range			10.5	
PSRR	Dower aupply rejection ratio	\\\ = \(\Gamma \)\\\	T _A = 25°C	85	95		dB
	Power-supply rejection ratio	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range	80			uБ

- (1) Slew rate is measured from an output level range of 25% to 75%.
- (2) Keep junction temperature less than the absolute maximum rating when the output is heavily loaded or shorted; see also Section 5.1.

5.9 Electrical Characteristics - THS4032, R_L = 1k Ω

at T_A = full range, V_{CC} = ±15 V, and R_L = 1 k Ω (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
DYNAN	IIC PERFORMANCE						
	Unity gain bandwidth	V _{CC} = ±15V, closed loop		100 ⁽¹⁾	120		MHz
514/	Small-signal bandwidth	Gain = -12V/V or 2V/V	V _{CC} = ±15V		100		
BW	(–3dB)		V _{CC} = ±5V		90		MHz
	D 1 : 111 C 0 4 ID G 1	Gain = -1V/V or 2V/V	V _{CC} = ±15V		50		
	Bandwidth for 0.1dB flatness		V _{CC} = ±5V		45		MHz
	[]	$V_{CC} = \pm 15V, V_{O(pp)} = 20V$	<u>'</u>		2.3		MIL
	Full power bandwidth ⁽²⁾	$V_{CC} = \pm 5V, V_{O(pp)} = 5V$			7.1		MHz
SR	Slew rate	V _{CC} = ±15V		80 ⁽¹⁾	100		V/µs
		To 0.1%, Gain = -1V/V	V _{CC} = ±15V, 5V step		60		
	0-441:		V _{CC} = ±5V, 2.5V step		45		ns
ts	Settling time	To 0.01%,Gain = -1V/V	V _{CC} = ±15V, 5V step		90		
			V _{CC} = ±5V, 2.5V step		80		
NOISE	AND DISTORTION PERFORMANC	E	<u>'</u>	'			
THD	Total harmonic distortion	V _{CC} = ±5 V or ±15 V, f = 1 MHz, Gain = 2V/V, V _{O(pp)} = 2 V, T _A = 25°C			-96		dBc
DC PEF	RFORMANCE						
		.45\/\/ .40\/	T _A = 25°C	93	98		
	0	$V_{CC} = \pm 15V, V_{O} = \pm 10V$	T _A = full range	92			٦D
	Open loop gain	pen loop gain	T _A = 25°C	92	95		dB
		$V_{CC} = \pm 5V, V_{O} = \pm 2.5V$	T _A = full range	91			
.,	land offer to the second		T _A = 25°C		0.5	2	\/
Vos	Input offset voltage	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range			3	mV
	I		T _A = 25°C		3	6	
I _{IB}	Input bias current	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range			8	μA
I _{OS}	Input offset current)/ .F\/ .45\/	T _A = 25°C		30	250	Λ
		$V_{CC} = \pm 5V \text{ or } \pm 15V$ $T_A = \text{full range}$				400	nA
	Input offset current drift	$V_{CC} = \pm 5V$ or $\pm 15V$, $T_A = full range$	ange		0.2		nA/°C
	Offset voltage drift	V_{CC} = ±5V or ±15V, T_A = full r	ange		2		μV/°C

Submit Document Feedback



5.9 Electrical Characteristics - THS4032, $R_L = 1k\Omega$ (continued)

at T_A = full range, V_{CC} = ±15 V, and R_L = 1 k Ω (unless otherwise noted)

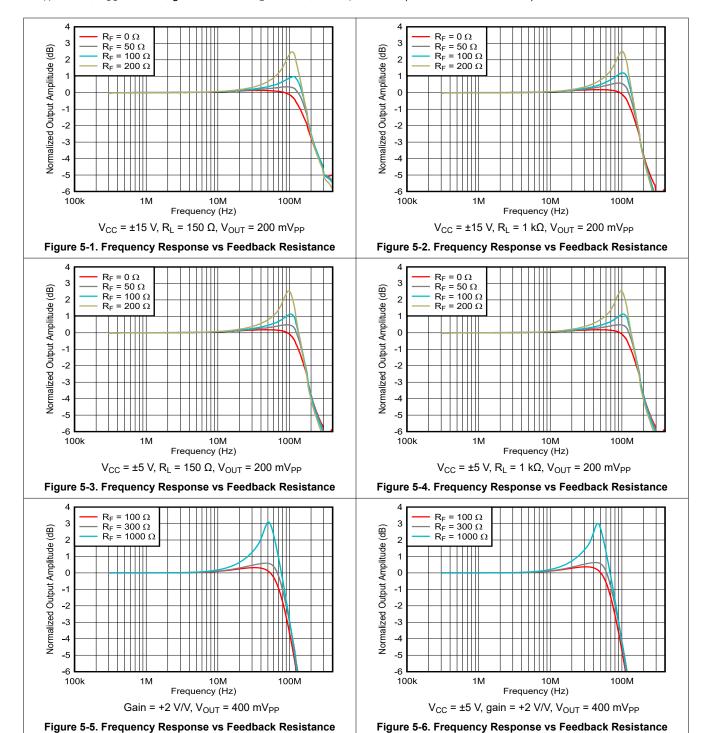
PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
INPUT C	HARACTERISTICS			<u> </u>			
.,	Common-mode input voltage range	$V_{CC} = \pm 15V$ $V_{CC} = \pm 5V$		±13.5	±14.3		V
V_{ICR}				±3.8	±4.3		
		14 .451414 .4014	T _A = 25°C	85	95		
CMDD	0	$V_{CC} = \pm 15V$, $V_{ICR} = \pm 12V$	T _A = full range	80			dB
CMRR	Common-mode rejection ratio	V - 15V V - 125V	T _A = 25°C	90	100		ав
		V_{CC} = ±5V, V_{ICR} = ±2.5V	T _A = full range	85			
Ri	Input resistance		'		2		МΩ
Ci	Input capacitance				1.5		pF
OUTPUT	CHARACTERISTICS						
.,	Output voltage swing	V _{CC} = ±15V		±13 ±13.6			V
Vo		V _{CC} = ±5V		±3.4	±3.8		V
	Output current ⁽²⁾	R ₁ = 20Ω	V _{CC} = ±15V	60	90		mA
I ₀		$V_{CC} = \pm 5V$		50	70		mA
I _{SC}	Short-circuit current ⁽³⁾	V _{CC} = ±15V	/ _{CC} = ±15V		150		mA
Ro	Output resistance	Open loop	Open loop		13		Ω
POWER	SUPPLY						
V	Cumply voltage energting range	Dual supply	Dual supply			±16.5	V
V_{CC}	Supply voltage operating range	Single supply		9		33	V
		V = 145V	T _A = 25°C		8.5	10	
	Supply current (each amplifier)	V _{CC} = ±15V	T _A = full range			11	4
Icc		V _{CC} = ±5V	T _A = 25°C		7.5	9	mA
			T _A = full range			10	
PSRR	Dower cumply rejection reti-	V = 15\/ or 145\/	T _A = 25°C	85	95		40
POKK	Power-supply rejection ratio	$V_{CC} = \pm 5V \text{ or } \pm 15V$	T _A = full range	80			dB

This minimum value is not tested. (1)

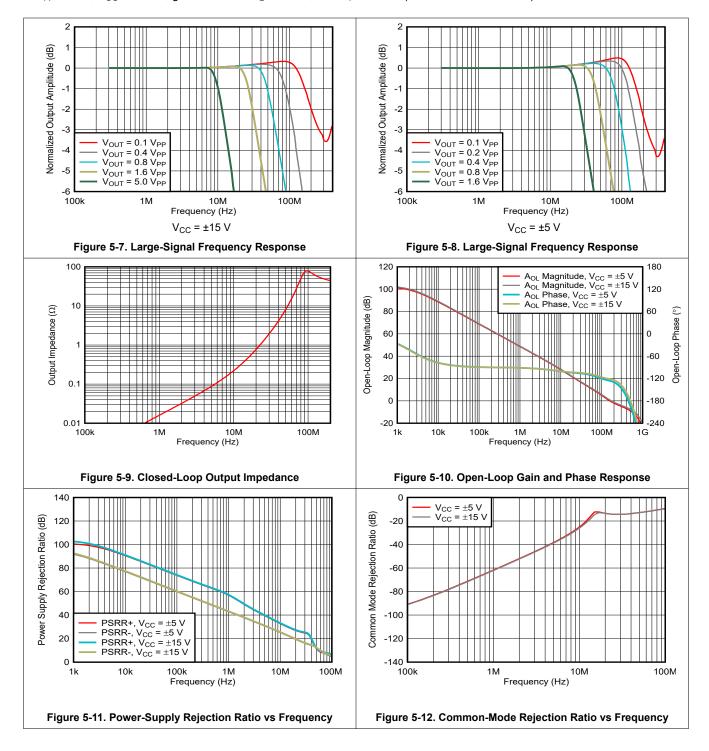
 ⁽²⁾ Full power bandwidth = slew rate / [√ 2̄ πV_{OC(Peak)}].
 (3) Keep junction temperature less than the absolute maximum rating when the output is heavily loaded or shorted; see also Section 5.1.



5.10 Typical Characteristics - THS4031

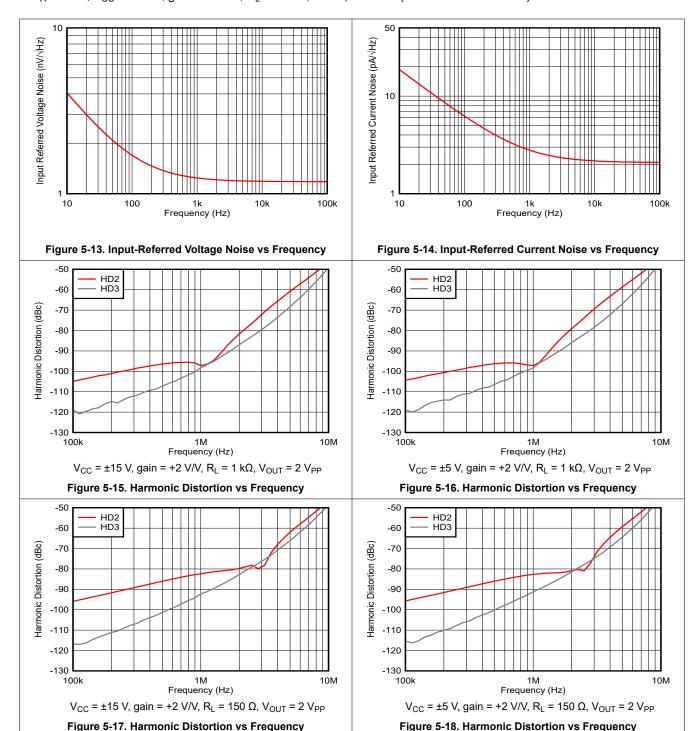








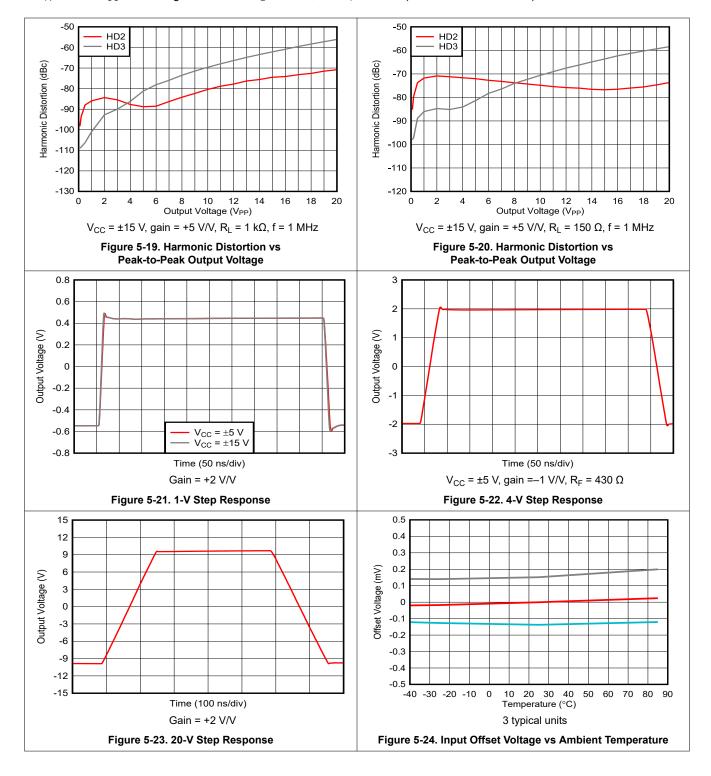
at T_A = 25°C, V_{CC} = ± 15 V, gain = +1 V/V, R_L = 150 Ω , and R_F = 300 Ω (unless otherwise noted)



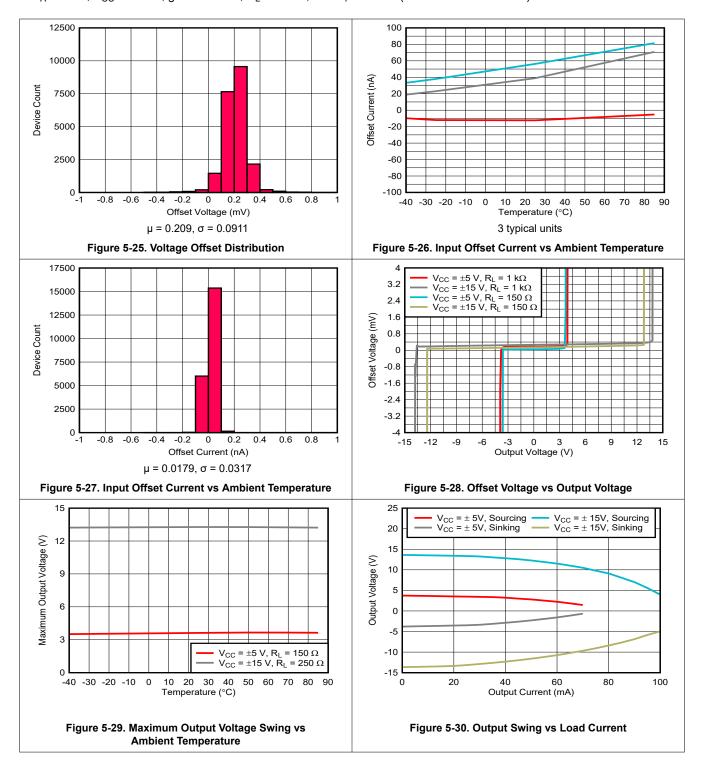
Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated

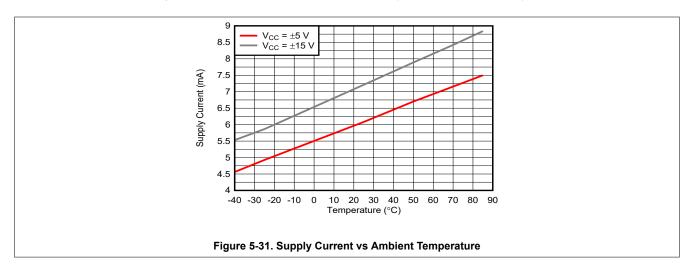














5.11 Typical Characteristics - THS4032

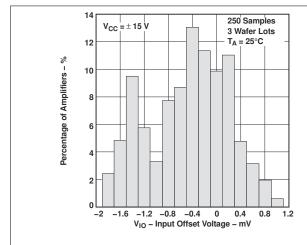


Figure 5-32. Input Offset Voltage Distribution

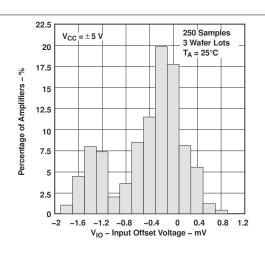


Figure 5-33. Input Offset Voltage Distribution

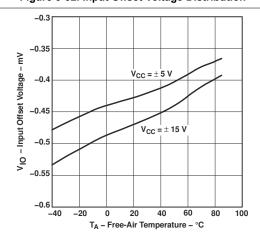


Figure 5-34. Input Offset Voltage vs Free-Air Temperature

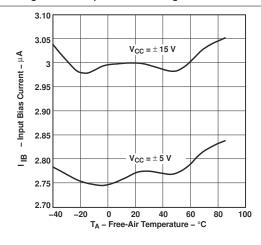


Figure 5-35. Input Bias Current vs Free-Air Temperature

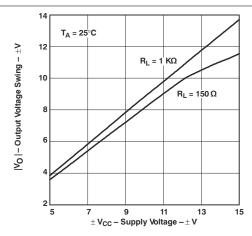


Figure 5-36. Output Voltage Swing vs Supply Voltage

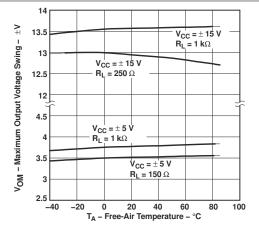


Figure 5-37. Maximum Output Voltage Swing vs Free-Air Temperature



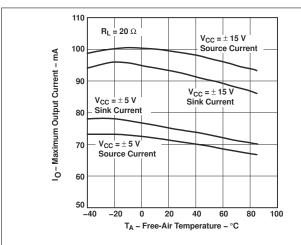


Figure 5-38. Maximum Output Current vs Free-Air Temperature

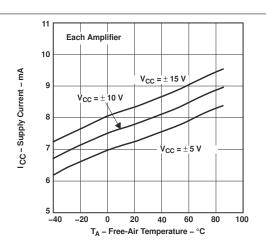


Figure 5-39. Supply Current vs Free-Air Temperature

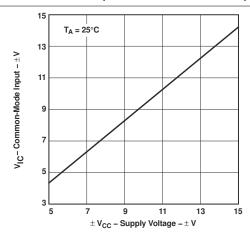


Figure 5-40. Common-Mode Input Voltage vs Supply Voltage

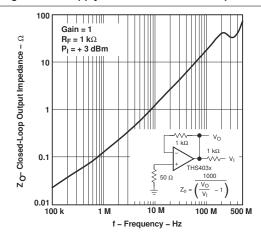


Figure 5-41. Closed-Loop Output Impedance vs Frequency

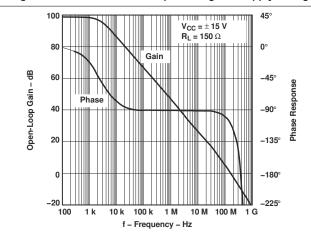


Figure 5-42. Open-Loop Gain and Phase Response

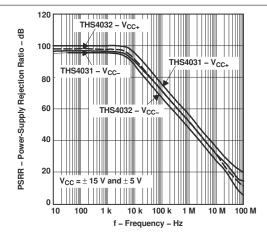


Figure 5-43. Power-Supply Rejection Ratio vs Frequency



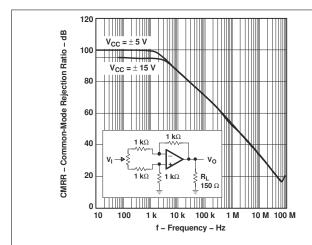


Figure 5-44. Common-Mode Rejection Ratio vs Frequency

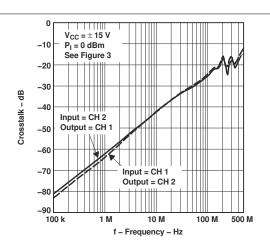


Figure 5-45. THS4032 Crosstalk vs Frequency

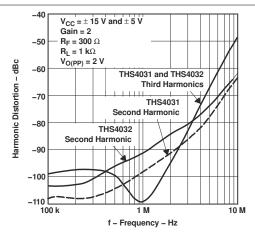


Figure 5-46. Harmonic Distortion vs Frequency

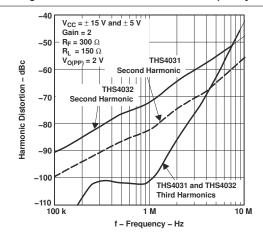


Figure 5-47. Harmonic Distortion vs Frequency

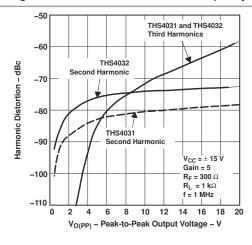


Figure 5-48. Harmonic Distortion vs Peak-to-Peak Output Voltage

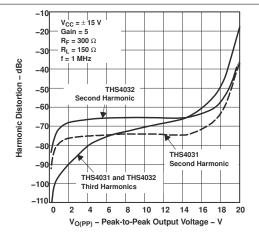


Figure 5-49. Harmonic Distortion vs Peak-to-Peak Output Voltage



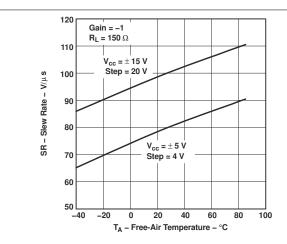


Figure 5-50. Slew Rate vs Free-Air temperature

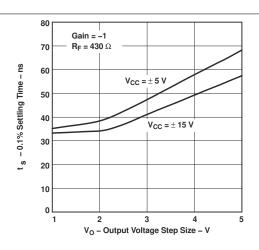


Figure 5-51. 0.1% Settling Time vs Output Voltage Step Size

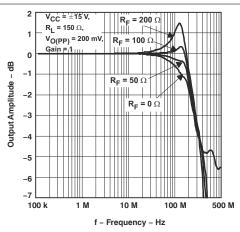


Figure 5-52. Small-Signal Frequency Response With Varying Feedback Resistance

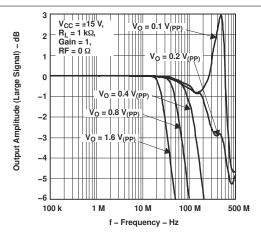


Figure 5-53. Frequency Response With Varying Output Voltage Swing

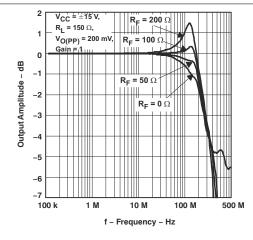


Figure 5-54. Small-Signal Frequency Response With Varying Feedback Resistance

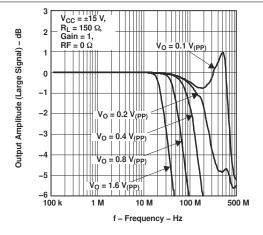


Figure 5-55. Frequency Response With Varying Output Voltage Swing



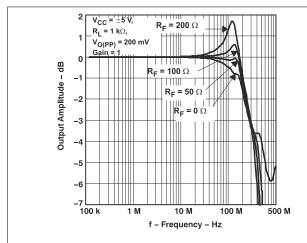


Figure 5-56. Small-Signal Frequency Response With Varying Feedback Resistance

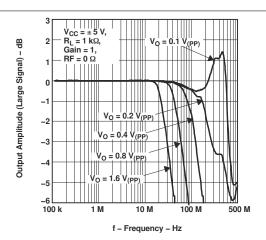


Figure 5-57. Frequency Response With Varying Output Voltage Swing

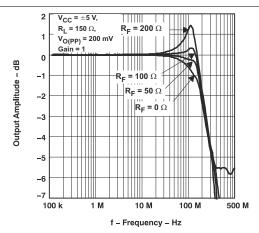


Figure 5-58. Small-Signal Frequency Response With Varying Feedback Resistance

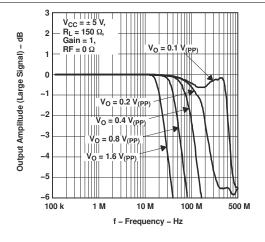


Figure 5-59. Frequency Response With Varying Output Voltage Swing

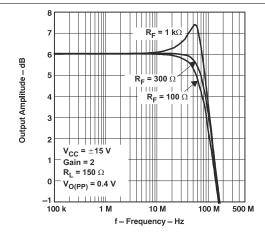


Figure 5-60. Small-Signal Frequency Response With Varying Feedback Resistance

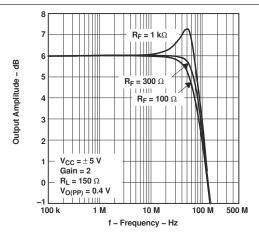


Figure 5-61. Small-Signal Frequency Response With Varying Feedback Resistance

Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated



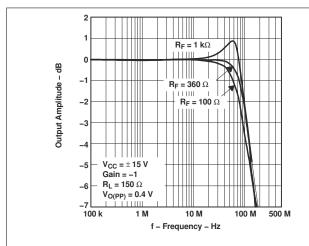


Figure 5-62. Small-Signal Frequency Response With Varying Feedback Resistance

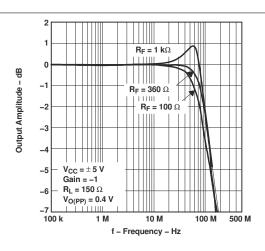


Figure 5-63. Small-Signal Frequency Response With Varying Feedback Resistance

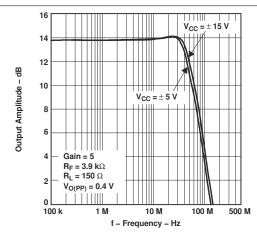


Figure 5-64. Small-Signal Frequency Response

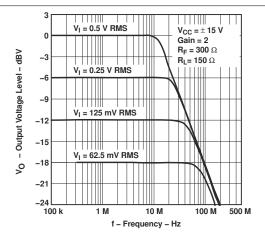


Figure 5-65. Output Amplitude vs Frequency

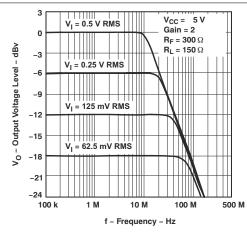


Figure 5-66. Output Amplitude vs Frequency

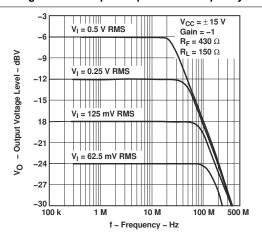
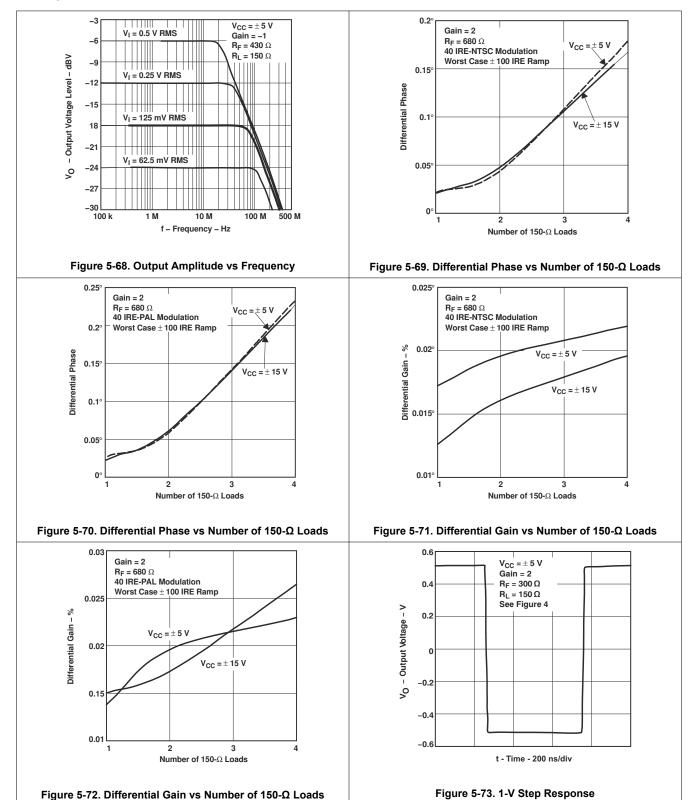
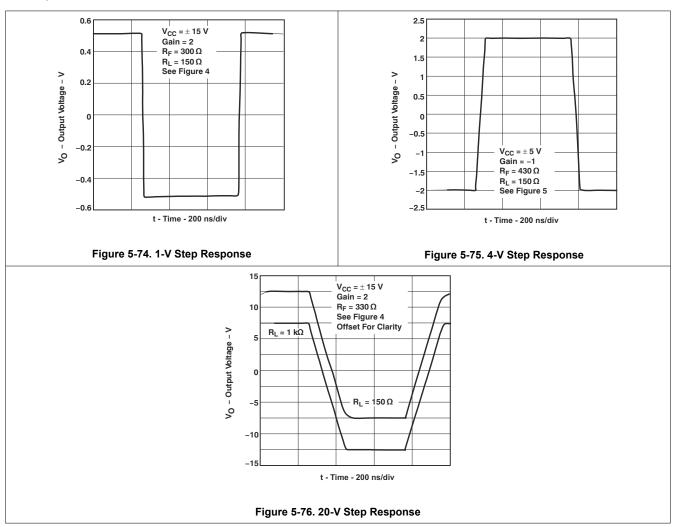


Figure 5-67. Output Amplitude vs Frequency









6 Detailed Description

6.1 Overview

The THS403x are high-speed operational amplifiers configured in a voltage-feedback architecture. These amplifiers are built using a 30-V, complementary bipolar process with NPN and PNP transistors that possess an f_T of several GHz. This configuration results in exceptionally high-performance amplifiers with wide bandwidth, high slew rate, fast settling time, and low distortion.

6.2 Functional Block Diagrams

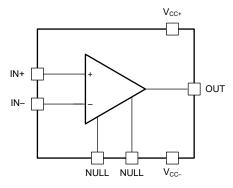


Figure 6-1. THS4031: Single Channel

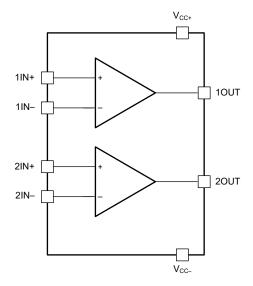


Figure 6-2. THS4032: Dual Channel

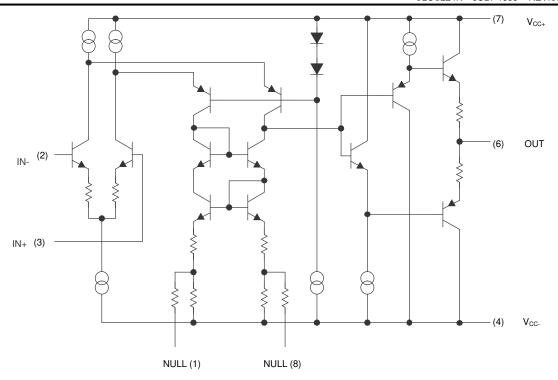


Figure 6-3. THS4031 Simplified Schematic

6.3 Feature Description

6.3.1 Offset Nulling

The THS403x have a very low input offset voltage for high-speed amplifiers. However, if additional correction is required, an offset nulling function has been provided on the THS4031. To adjust the input offset voltage, place a potentiometer between pin 1 and pin 8 of the device, and tie the wiper to the negative supply. Figure 6-4 shows this feature.

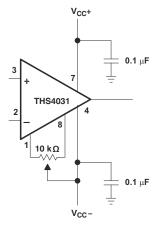


Figure 6-4. Offset Nulling Schematic

6.4 Device Functional Modes

The THS403x family has a single functional mode and can be used with both single-supply or split power-supply configurations. The power-supply voltage must be greater than $9 \text{ V} (\pm 4.5 \text{ V})$ and less than $33 \text{ V} (\pm 16.5 \text{ V})$.

7 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

7.1 Application Information

7.1.1 Driving a Capacitive Load

The THS403x devices are internally compensated to maximize bandwidth and slew-rate performance. Take additional precautions when driving capacitive loads with a high-performance amplifier to maintain stability. As a result of the internal compensation, significant capacitive loading directly on the output node decreases the device phase margin, and potentially leads to high-frequency ringing or oscillations. Therefore, for capacitive loads greater than 10 pF, place an isolation resistor in series with the output of the amplifier. Figure 7-1 shows this configuration. For most applications, a minimum resistance of 20 Ω is recommended. In 75- Ω transmission systems, setting the series resistor value to 75 Ω is a beneficial choice because this value isolates any capacitance loading and provides source impedance matching.

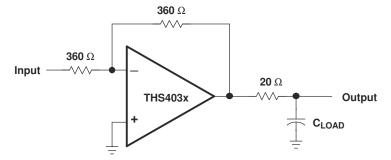


Figure 7-1. Driving a Capacitive Load

Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated

7.1.2 Low-Pass Filter Configurations

When receiving low-level signals, limiting the bandwidth of the incoming signals into the system is often required. Figure 7-2 shows that the simplest way to accomplish this limiting is to place an RC filter at the noninverting pin of the amplifier.

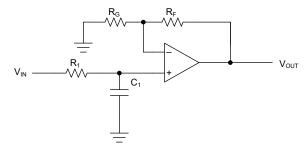


Figure 7-2. Single-Pole Low-Pass Filter

$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \times \left(\frac{1}{1 + sR_1C_1}\right) \tag{1}$$

If more attenuation at higher frequencies is required, a multiple-pole filter is required. Figure 7-3 shows a common implementation of a second-order filter called a Sallen-Key filter. When designing this type of filter, chose an amplifier who bandwidth is approximately an order of magnitude larger than the desired filter bandwidth. See Active Low-pass Filter Design for more detailed active-filter design information.

Assuming $R_1 = R_2 = R$ and $C_1 = C_2 = C$, use Equation 2 to set the bandwidth of the filter.

$$f_{3dB} = \frac{1}{2\pi RC} \tag{2}$$

The Q-factor of a filter controls the amount of peaking of the small-signal frequency response and the settling time of the pulse response. Set Q to 0.707 to provide a Butterworth response with a maximally flat pass band. Use Equation 3 to chose the ratio of R_F and R_G to obtain the desired Q value.

$$\frac{R_F}{R_G} = 2 - \frac{1}{Q}$$

$$V_{IN} = \frac{R_1}{R_2} = \frac{R_2}{R_2}$$

$$V_{OUT}$$

Figure 7-3. Two-Pole Low-Pass Sallen-Key Filter

7.2 Typical Application

This section demonstrates multiplexing several analog input signals to a high-performance driver amplifier which subsequently drives a single high-resolution, high-speed SAR analog-to-digital converter (ADC). This example uses the ADS8411 and the TS5A3159 or TS5A3359 as the ADC and the multiplexer, respectively. This application uses the THS403x as the operational amplifier.

As detailed in Figure 7-4, the example system consists of an ADC (ADS8411), a driving operational amplifier (THS4031), a multiplexer (TS5A3159), an ac source, a dc source, and two driving operational amplifiers.

The driving amplifiers OPA1 are OPA2 are shown as two THS4031 amplifiers. Alternatively, use a single THS4032 to save on cost and board space. The purpose of these op-amps is make the input sources present a low impedance to rest of the circuit. Additionally, to maintain signal fidelity, these operational amplifiers must have low noise and distortion. The third THS4031 labeled OPA3 in Figure 7-4 is used to maintain switching speed and drive the ADC. The passive band-pass filter before the ADC reduces unwanted noise.

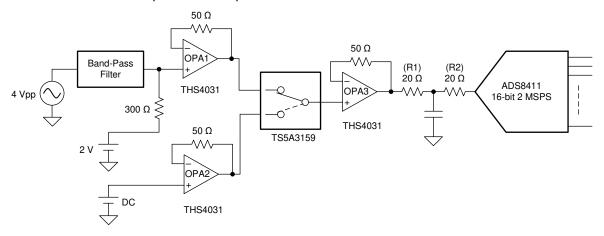


Figure 7-4. Multiplexing Setup to Drive a High-Performance ADC

7.2.1 Design Requirements

The objective to is design a multiplexed digitizer system with the dynamic performance shown in Table 7-1.

DEVICE SPEED (MSPS)	INPUT FREQUENCY (kHz)	SNR (dB)	THD (dB)	CROSSTALK (dB)
2	20	> 84	< –90	< -110
2	100	> 84	< -90	< –96

Table 7-1. Design Specifications

7.2.2 Detailed Design Procedure

The ADS8411 is a 16-bit, 2-MSPS analog-to-digital converter (ADC) with a 4-V reference. The ADS8411 has a unipolar single-ended input and includes a 16-bit capacitor-based SAR ADC, with inherent sample and hold. The output is a 16-bit parallel interface.

The TS5A3159 is a single-pole, double-throw (SPDT) analog switch that is designed to operate from 1.65 V to 5.5 V. The TS5A3159 offers a low ON state resistance and an excellent ON resistance matching with the break-before-make feature to prevent signal distortion during the transfer of a signal from one channel to another. Additionally, the TS5A3159 provides excellent total harmonic distortion (THD) performance and consumes low power. The TS5A3359 is a single-pole, triple-throw (SP3T) version of the same switch.

7.2.2.1 Selection of Multiplexer

Figure 7-5 shows an equivalent circuit diagram of one of the channels of a multiplexer. C_S is the input capacitance of the channel; CD is the output capacitance of the channel. RON is the resistance of the channel when the channel is turned ON. C_L and R_L are the load capacitance and resistance, respectively. V_{IN} is the input voltage of the source. R_S is the resistance of the source. V_{OUT} is the output voltage of the multiplexer.

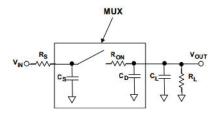


Figure 7-5. Multiplexer Equivalent Circuit

Settling time is improved when the values of R_S, R_{ON}, C_S, C_D, and C_L are small, and the value of R_L is large.

For TS5A3159:

- R_{ON} = 1 Ω
 C_S = C_D = 84 pF

Typical values for the extrinsic parameters are

- $R_S = 50 \Omega$
- $C_L = 5 pF$
- $R_L = 10 \text{ k}\Omega$
- T_{RC} (time constant) = 8.65 ns

For a 16-bit system, at least 18-bit settling is desired to minimize distortion from settling artifacts. For an 18-bit settling, the circuit response time required is $(18 \times ln2) \times T_{RC} = 108$ ns, which is less than 2 MSPS sampling time of 500 ns. If the settling time is more than the conversion time of the ADC, the output of the multiplexer does not settle to the required accuracy resulting in distortion.

One more important parameter to consider when selecting a multiplexer is the on-state resistance variation with voltage. This variation also affects distortion because R_{ON} and R_L act like a resistor divider circuit. Any variation of R_{ON} with voltage affects the output voltage.

7.2.2.2 Signal Source

The input signal source must be a low-noise, low-distortion source with low source resistance. As discussed in the earlier section, the rouse resistance also must be small to avoid impacting settling time. If the source is not a low-noise and low-distortion source, a passive band-pass filter can be added to improve the signal quality as shown in Figure 7-4.

7.2.2.3 Driving Amplifier

The driving operational amplifier (OPA3 in Figure 7-4) in this application must have good slew rate, bandwidth, low noise, and distortion. The input of the operational amplifier can result in a maximum step of 4-V because of MUX switching. As a result, even if the signal bandwidth is low, the driving amplifier must settle from a 4-V step within one ADC sampling frame to avoid signal distortion. In this example, the settling requirement due to the ADC selection is 500 ns. The THS4031 is a good choice in this application due to the high slew rate and low distortion of this operational amplifier.

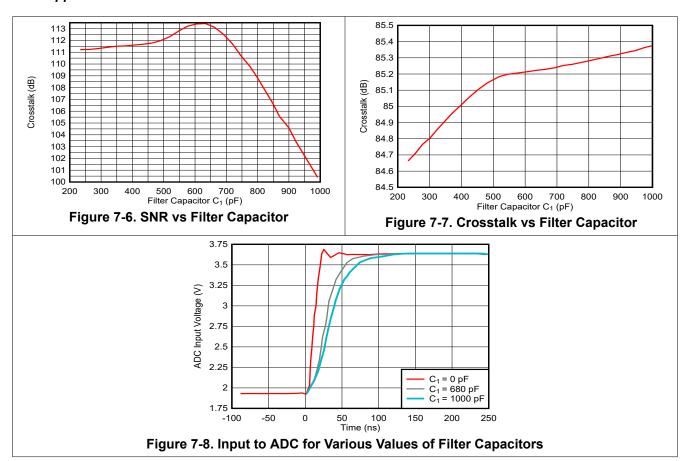
7.2.2.4 Driving Amplifier Bandwidth Restriction

The restriction of excess bandwidth by use of a passive RC filter before the ADC results in better SNR and THD. However, restricting the bandwidth too much results in a excessive operational amplifier settling time. If the amplifier output does not settle quick enough, some residual charge of the previous channel remains in the next sampling interval and appears as crosstalk. One approach to solve this settling issue is to reduce the throughput of the ADC. However, often the high sample rate ADC was chosen to the need to acquire higher frequency signals limiting the freedom to reduce the ADC throughput. Due to these tradeoffs, the choice of the filter capacitor becomes critical. Figure 7-6 and Figure 7-7 show SNR and crosstalk as a function of the filter capacitor.

Figure 7-8 shows input settling behavior with three different filter capacitor values. The value of the capacitor changes to filter bandwidth. As the filter bandwidth increases, the settling time improves as shown in Equation 4.

Filter Bandwidth
$$\cong \frac{1}{2\pi R_1 C_1}$$
 (4)

7.2.3 Application Curves



Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated



7.3 Power Supply Recommendations

The THS403x family operates off a single supply or with dual supplies. Choose supplies that provide for the required headroom to supply rails as specified by the common-mode input range (CMIR). Operating from a single supply has numerous advantages. With the negative supply at ground, the dc errors due to the –PSRR term are minimized. Decouple supplies with low inductance capacitors to ground as close to the amplifier as possible. When operating on a board with high-speed digital signals, provide isolation between digital signal noise and the analog input pins. When using a ground plane, remove the ground plane close to input sensitive pins to reduce stray parasitics that adversely impact device performance. For split-supply operation, an optional supply decoupling capacitor across the two power supplies improves second harmonic distortion performance.

7.4 Layout

7.4.1 Layout Guidelines

To achieve the levels of high-frequency performance of the THS403x, follow proper printed-circuit board (PCB), high-frequency design techniques. The following is a general set of guidelines. In addition, a THS403x evaluation board is available to use as a guide for layout or for evaluating the device performance.

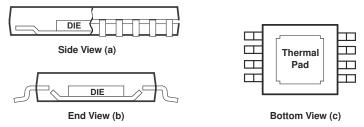
- **Ground planes**—make sure that the ground plane used on the board provides all components with a low-inductive ground connection. However, in the areas of the amplifier inputs and output, the ground plane can be removed to minimize stray capacitance.
- **Proper power-supply decoupling**—use a 6.8-µF tantalum capacitor in parallel with a 0.1-µF ceramic capacitor on each supply pin. Sharing the tantalum capacitor among several amplifiers is possible depending on the application, but always use a 0.1-µF ceramic capacitor on the supply pin of every amplifier. In addition, place the 0.1-µF capacitor as close as possible to the supply pin. As this distance increases, the inductance in the connecting trace makes the capacitor less effective. Strive for distances of less than 0.1 inch (2.54 mm) between the device power pins and the ceramic capacitors.
- Short trace runs or compact part placements—optimum high-frequency performance is achieved when stray series inductance is minimized. To minimize stray inductance, make the circuit layout as compact as possible, thereby minimizing the length of all trace runs. Pay particular attention to the inputs of the amplifier, keeping the trace lengths as short as possible. This layout helps to minimize stray capacitance at the input of the amplifier.
- **Sockets**—TI does not recommend sockets for high-speed operational amplifiers. The additional lead inductance in the socket pins often leads to stability problems. Surface-mount packages soldered directly to the printed-circuit board is the best implementation.
- Short trace runs and compact part placements—Improved high-frequency performance is achieved when stray series inductance is minimized. To reduce stray series inductance, the circuit layout must be made as compact as possible, thereby minimizing the length of all trace runs. Particular attention must be paid to the inverting input of the amplifier. The length must be kept as short as possible to minimize stray capacitance at the input of the amplifier.

7.4.1.1 General PowerPAD™ Integrated Circuit Package Design Considerations

The THS403x are available in a thermally-enhanced DGN package, which is a member of the PowerPAD™ integrated circuit package family. This package is constructed using a downset lead frame upon which the die is mounted [see Figure 7-9(a) and Figure 7-9(b)]. This arrangement results in the lead frame exposed as a thermal pad on the underside of the package [see Figure 7-9(c)]. Because this thermal pad has direct thermal contact with the die, excellent thermal performance can be achieved by providing a good thermal path away from the thermal pad.

The PowerPAD integrated circuit package allows for both assembly and thermal management in one manufacturing operation. During the surface-mount solder operation (when the leads are soldered), the thermal pad can be soldered to a copper area under the package. By using thermal paths within this copper area, heat is conducted away from the package into a ground plane or other heat-dissipating device.

The PowerPAD integrated circuit package represents a breakthrough in combining the small area and ease of assembly of surface mount with the more-recent, awkward mechanical methods of sinking heat.



Note: The thermal pad is electrically isolated from all pins in the package.

Figure 7-9. Views of Thermally-Enhanced DGN Package

Although there are many ways to properly dissipate heat from this device, the following steps show the recommended approach.

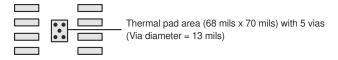


Figure 7-10. PowerPAD™ PCB Etch and Via Pattern

- 1. Prepare the PCB with a top-side etch pattern as shown in Figure 7-10. There must be etch for the leads as well as etch for the thermal pad.
- 2. Place five holes in the area of the thermal pad. These holes must be 13 mils (0.3302 mm) in diameter. The reason to keep the holes small is to discourage solder wicking through the holes during reflow.
- 3. Additional vias can be placed anywhere along the thermal plane outside of the thermal pad area. This action helps dissipate the heat generated by the THS403x device. The additional vias can be of any diameter because wicking is not a concern outside of the thermal pad area.
- 4. Connect all holes to the internal ground plane.
- 5. When connecting these holes to the ground plane, *do not* use the typical web or spoke via connection methodology. Web connections have a high thermal-resistance connection that is useful for slowing the heat transfer during soldering operations. This makes the soldering of vias that have plane connections easier. In this application, however, low thermal resistance is desired for the most efficient heat transfer. Therefore, the holes under the THS403x package must connect to the internal ground plane with a complete connection around the entire circumference of the plated-through hole.
- 6. The top-side solder mask must leave the pins of the package and the thermal pad area with the five holes exposed. The bottom-side solder mask must cover the five holes of the thermal pad area, which prevents solder from pulling away from the thermal pad area during the reflow process.
- 7. Apply solder paste to the exposed thermal pad area and to all the device pins.
- 8. With these preparatory steps in place, the THS403x device is placed in position and run through the solder reflow operation as any standard surface-mount component.

Submit Document Feedback



7.4.2 Layout Example

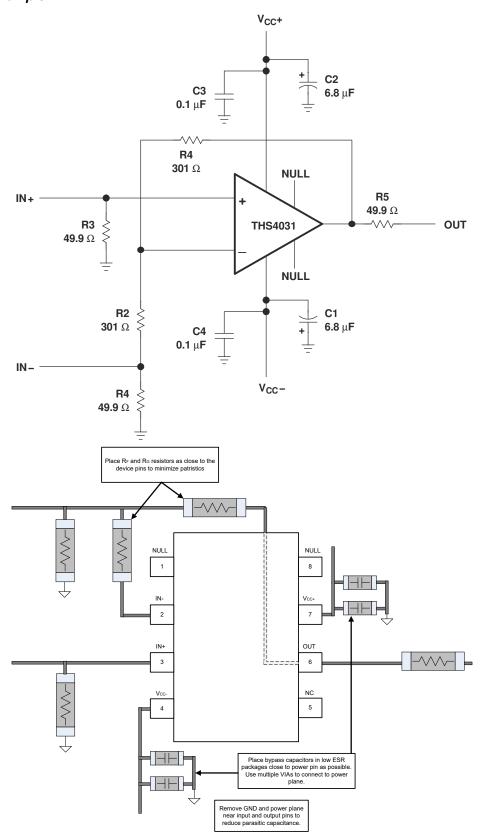


Figure 7-11. Layout Recommendations



8 Device and Documentation Support

8.1 Documentation Support

8.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Noise Analysis for High-Speed Op Amps, application report
- Texas Instruments, *PowerPAD™ Thermally-Enhanced Package*, application report
- Texas Instruments, THS4031 High-Speed Op Amp, EVM user's guide
- Texas Instruments, THS4032 Dual High-Speed Op Amp, EVM user's guide

8.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

8.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

8.4 Trademarks

PowerPAD™ and TI E2E™ are trademarks of Texas Instruments.

All trademarks are the property of their respective owners.

8.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

8.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

9 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision J (February 2024) to Revision K (May 2024)	Page
•	Deleted Total harmonic distortion + noise and Intermodulation distortion specifications from <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω	6
•	Deleted Total harmonic distortion + noise and Intermodulation distortion specifications from <i>Electrical Characteristics - THS4031</i> , $R_L = 1 k\Omega$	7
•	Changed gain from +2 V/V to +1 V/V in Typical Characteristics - THS4031	
•	Changed abscissa axis label from 10 ns/div to 100 ns/div in Figure 5-23, 20V Step Response	
С	hanges from Revision I (May 2018) to Revision J (February 2024)	Page
•	Updated the numbering format for tables, figures, and cross-references throughout the document Changed table note 1 in Absolute Maximum Ratings to add additional clarification	

Submit Document Feedback

Copyright © 2024 Texas Instruments Incorporated

Changed output current max in Absolute Maximum Ratings from 150 mA to 240 mA......4



www.ti.com

•	Changed differential supply voltage in <i>Absolute Maximum Ratings</i> from ± 4 V to ± 1.5 V	.4
•	Added continuous input current in Absolute Maximum Ratings	. 4
•	Deleted M-suffix temperature range and in Absolute Maximum Ratings	. 4
•	Deleted JG and FK package references in Absolute Maximum Ratings	.4
•	Changed charged-device model (CDM) reference from JESD22-C101 to JS-002 in <i>ESD Ratings</i>	.4
•	Updated Thermal Information: THS4031 for the D and DGN packages	. 5
•	Deleted full-power bandwidth specification from <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω	6
•	Added Electrical Characteristics - THS4031, RL = 150 Ω section	6
•	Changed bandwidth for 0.1-dB flatness in <i>Electrical Characteristics - THS4031, R</i> _L = 150 Ω from 50 MHz to	9
	MHz for V_{CC} = ±15 V	. 6
•	Changed bandwidth for 0.1-dB flatness in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 45 MHz to)
	9 MHz for V _{CC} = ±5 V	.6
•	Changed settling time to 0.1% in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 60 ns to 70 ns for	
	V _{CC} = ±15 V	.6
•	Changed settling time to 0.1% in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 45 ns to 55 ns for	
	$V_{CC} = \pm 5 \text{ V}$.6
•	Deleted total harmonic distortion for 1 k Ω in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω	.6
•	Changed input voltage noise - in <i>Electrical Characteristics</i> - THS4031, $R_L = 150 \Omega$ from 1.6 nV/ $\sqrt{\text{Hz}}$ to 1.2	
	nV/√Hz	.6
•	Changed input current noise in <i>Electrical Characteristics - THS4031</i> , $R_L = 150 \Omega$ from 1.2 pA/ $\sqrt{\text{Hz}}$ to 2.3	
	pA/√Hz	. 6
	Changed open loop gain condition in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 1 k Ω to 150 Ω	.6
	Changed open loop gain minimum in <i>Electrical Characteristics - THS4031, R_L = 150</i> Ω from 98 dB to 100 d	
	4 1/ 4 1/ 4 1/ 4 1/ 4 1/ 4 1/ 4 1/ 4 1/	6
	Changed open loop gain minimum specification in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 9	_
		.6
	Updated input offset voltage values and units specification in <i>Electrical Characteristics - THS4031</i> , R_L = 150	
	O	6
	Added input offset current specification in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω table	6
	Changed common-mode input voltage range typical in <i>Electrical Characteristics - THS4031,R</i> _L = 150 Ω from	
	±14 V to ±14.3 V for V _{CC} = ±15 V	6
	Changed common-mode input voltage range typical in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω	. •
	from ± 4 V to ± 4.3 V for $V_{CC} = \pm 5$ V	6
		6
	Changed output voltage swing condition for $V_{CC} = \pm 15 \text{ V}$ in <i>Electrical Characteristics - THS4031</i> , $R_L = 150 \text{ G}$	
•	from 150 Ω to 250 Ω	<u>ہ</u>
	Changed output voltage swing condition for V_{CC} = ±5 V in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω	. U
•	from 250 Ω to 150 Ω	
	Deleted short circuit current in <i>Electrical Characteristics</i> - <i>THS4031</i> , R_L = 150 Ω	
•		
•	Changed output current load resistance typical in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 20	
	to 10 Ω	
•	Changed output current typical in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 90 mA to 200 mA for R_L = 150 R_L from 90 mA to 200 mA for R_L = 150 R_L	
	$V_{CC} = \pm 15V$.0
•	Changed output current typical in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 70 mA to 160 mA for	
	$V_{CC} = \pm 5V$.6
•	Changed output resistance typical in <i>Electrical Characteristics - THS4031</i> , $R_L = 150 \Omega$ from 13 Ω to 5 Ω	
•	Changed supply current (each amplifier) typical in <i>Electrical Characteristics - THS4031</i> , $R_L = 150 \Omega$ from 8.	
	mA to 7.5 mA for $V_{CC} = \pm 15 \text{ V}$	
•	Changed supply current (each amplifier) typical in <i>Electrical Characteristics - THS4031</i> , R_L = 150 Ω from 7.	
	mA to 6.5 mA for V_{CC} = ±5 V_{CC}	6
•	Changed bandwidth for 0.1-dB flatness in <i>Electrical Characteristics - THS4031</i> , R_L = 1 $k\Omega$ from 50 MHz to 9	
	MHz for V_{CC} = ±15 V	7



•	Changed bandwidth for 0.1-dB flatness in <i>Electrical Characteristics - THS4031</i> , R_L = 1 $k\Omega$ from 45 MHz to 9 MHz for V_{CC} = ±5 V_{CC}	7
•	Changed full power bandwidth calculation from slew rate / $[\sqrt{\pi}V_{OC(Peak)}]$ to slew rate / $[\pi V_{O(P-P)}]$ in <i>Electrical</i>	'
	Characteristics - THS4031, R_1 = 1 k Ω	7
•	Changed full power bandwidth in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 k\Omega$ from 2.3 to 1.6 for $V_{CC} = \pm 15 \text{ V}$.	7
•	Changed full power bandwidth specification in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 k\Omega$ from 7.1 to	'
	5.1 for V _{CC} = ±5 V	7
•	Changed 0.1% setting time in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 k\Omega$ from 60 to 70 for $V_{CC} = \pm 15 \text{ V}$	7
•	Changed 0.1% setting time in <i>Electrical Characteristics - THS4031</i> , R_L = 1 $k\Omega$ from 45 to 55 for V_{CC} = ±15 V_{CC}	7
	±15 V Deleted total harmonic distortion, voltage noise, current noise, differential gain error, and differential phase	1
	error for $R_L = 150 \Omega$ in <i>Electrical Characteristics - THS4031,</i> $R_L = 1 k\Omega$	7
•	Changed open loop gain minimum in <i>Electrical Characteristics - THS4031, R_L = 1 k</i> Ω from 98 dB to 100 dB	
_	for VCC = ±15 V, T _A = 25 °C	
•	Changed open loop gain minimum in <i>Electrical Characteristics - THS4031</i> , R_L = 1 $k\Omega$ from 95 dB to 98 dB fo V_{CC} = ±5 V, T_A = 25 °C	
•	Changed input offset voltage typical in <i>Electrical Characteristics - THS4031</i> , $R_L = 1k \Omega$ from 0.5 mV to	•
	0.3 mV	7
•	Changed input bias current typical in <i>Electrical Characteristics - THS4031</i> , R_L = 1 $k\Omega$ from 3 μ A to 9 μ A for T_A = 25°C	7
	Changed input bias current max in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 \text{ k}\Omega$ from 6 μ A to 20 μ A for T_A	
	= 25°C	7
•	Changed input bias current max in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 k\Omega$ from 8 μ A to 33 μ A for T _j = full range	A 7
•	Deleted output voltage swing for R _L = 150 Ω and R _L = 250 Ω in <i>Electrical Characteristics - THS4031, R_L</i> = 1 $k\Omega$ table	
•	Deleted output current in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 \text{ k}\Omega$ table	
•	Deleted output resistance in <i>Electrical Characteristics - THS4031</i> , R_L =1 $k\Omega$	
•	Changed supply current (each amplifier) typical in <i>Electrical Characteristics - THS4031</i> , R_L = 1 $k\Omega$ from 8.5 mA to 7.5 mA for V_{CC} = ±15 V_{CC}	7
•	Changed supply current (each amplifier) in <i>Electrical Characteristics - THS4031</i> , $R_L = 1 \text{ k}\Omega$ from 7.5 mA to	
	6.5 mA for V_{CC} = ±5 V	
•	Deleted full-power bandwidth specification from <i>Electrical Characteristics - THS4032</i> , $R_L = 150\Omega$	
•	Changed title of Electrical Characteristics - R_L = 150 Ω to Electrical Characteristics - THS4032, R_L = 150 Ω	
•	Updated input offset voltage units specification in <i>Electrical Characteristics - THS4032</i> , $R_L = 150\Omega$	
•	Boloted That opon toop gam opening and them in Electrical Characteristics 1770 1002, The	9
•	Changed title of Electrical Characteristics: $R_L = 1k\Omega$ to Electrical Characteristics - THS4032 $R_L = 1k\Omega$ 1	0
•	Deleted 150Ω input voltage noise, input current noise, differential gain error, and differential phase error,	_
	specifications from Electrical Characteristics - THS4032, $R_L = 1k\Omega$	U
•	Deleted output voltage swing for R_L = 150 Ω and R_L = 250 Ω in <i>Electrical Characteristics - THS4032</i> , R_L = 1 $k\Omega$ table	n
	Added Typical Characteristics - THS4031 section	
	Changed title of <i>Typical Characteristics</i> to <i>Typical Characteristics - THS4032</i>	
	Deleted Parameter Measurement Information section.	
	Deleted Noise Calculation and Noise Figure, Optimizing Frequency Response, and Offset Voltage sections 2	
•	Changed Application Information section to latest standard format	
•	Changed name of General Configuration section to Low-pass Filter Configurations	
•	Deleted thermal calculations in <i>General PowerPAD™ Integrated Circuit Package Design Considerations</i> 3	
	and the second s	Ť



10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 13-Mar-2024

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
THS4031CD	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	4031C	
THS4031CDGN	LIFEBUY	HVSSOP	DGN	8	80	RoHS & Green	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	0 to 70	ACM	
THS4031CDGNR	LIFEBUY	HVSSOP	DGN	8	2500	RoHS & Green	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	0 to 70	ACM	
THS4031ID	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	40311	
THS4031IDG4	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	40311	
THS4031IDGN	LIFEBUY	HVSSOP	DGN	8	80	RoHS & Green	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	ACN	
THS4031IDGNG4	LIFEBUY	HVSSOP	DGN	8	80	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ACN	
THS4031IDGNR	ACTIVE	HVSSOP	DGN	8	2500	RoHS & Green	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	ACN	Samples
THS4031IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	40311	Samples
THS4032ID	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	40321	
THS4032IDG4	LIFEBUY	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	40321	
THS4032IDGNR	ACTIVE	HVSSOP	DGN	8	2500	RoHS & Green	NIPDAU NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	ABG	Samples
THS4032IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	40321	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

PACKAGE OPTION ADDENDUM

www.ti.com 13-Mar-2024

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF THS4031, THS4032:

● Enhanced Product : THS4032-EP

Military: THS4031M

NOTE: Qualified Version Definitions:

- Enhanced Product Supports Defense, Aerospace and Medical Applications
- Military QML certified for Military and Defense Applications



www.ti.com 16-May-2024

TAPE AND REEL INFORMATION



TAPE DIMENSIONS KO P1 BO W Cavity A0

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

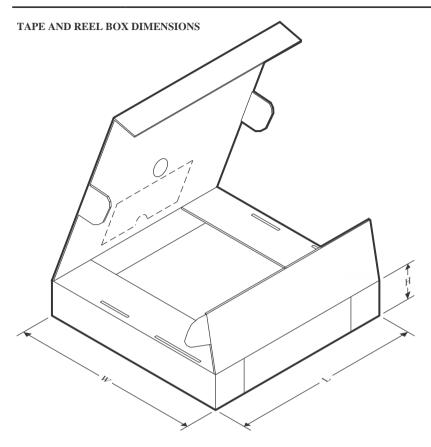


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THS4031CDGNR	HVSSOP	DGN	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
THS4031CDGNR	HVSSOP	DGN	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
THS4031IDGNR	HVSSOP	DGN	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
THS4031IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
THS4032IDGNR	HVSSOP	DGN	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
THS4032IDGNR	HVSSOP	DGN	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
THS4032IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1



www.ti.com 16-May-2024



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THS4031CDGNR	HVSSOP	DGN	8	2500	364.0	364.0	27.0
THS4031CDGNR	HVSSOP	DGN	8	2500	358.0	335.0	35.0
THS4031IDGNR	HVSSOP	DGN	8	2500	364.0	364.0	27.0
THS4031IDR	SOIC	D	8	2500	350.0	350.0	43.0
THS4032IDGNR	HVSSOP	DGN	8	2500	364.0	364.0	27.0
THS4032IDGNR	HVSSOP	DGN	8	2500	358.0	335.0	35.0
THS4032IDR	SOIC	D	8	2500	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

www.ti.com 16-May-2024

TUBE



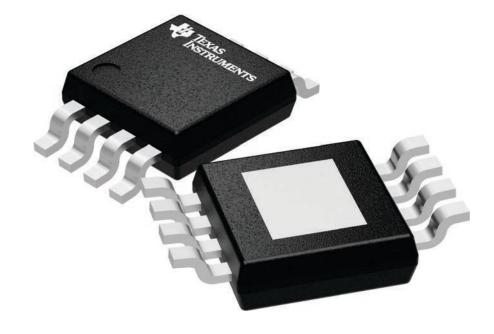
*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
THS4031CD	D	SOIC	8	75	505.46	6.76	3810	4
THS4031CDGN	DGN	HVSSOP	8	80	330	6.55	500	2.88
THS4031ID	D	SOIC	8	75	505.46	6.76	3810	4
THS4031IDG4	D	SOIC	8	75	505.46	6.76	3810	4
THS4031IDGN	DGN	HVSSOP	8	80	330	6.55	500	2.88
THS4031IDGNG4	DGN	HVSSOP	8	80	330	6.55	500	2.88
THS4032ID	D	SOIC	8	75	505.46	6.76	3810	4
THS4032IDG4	D	SOIC	8	75	505.46	6.76	3810	4

3 x 3, 0.65 mm pitch

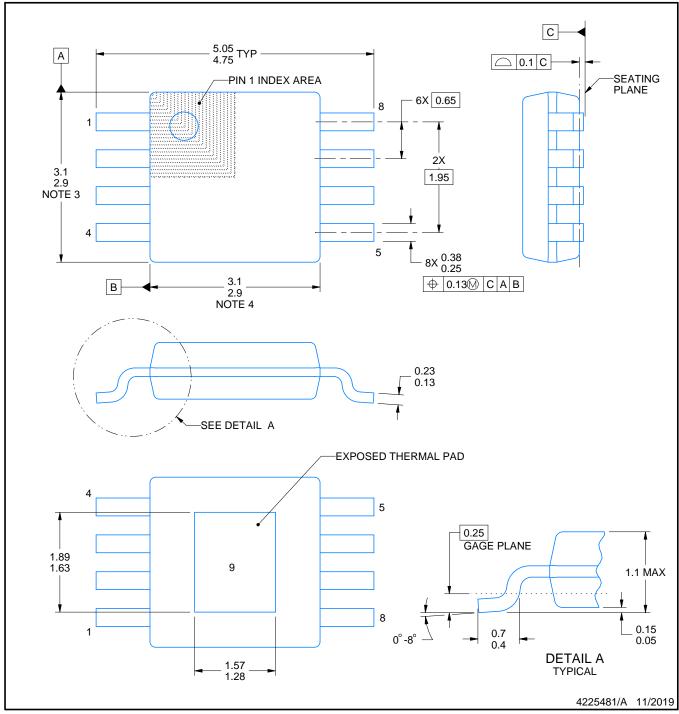
SMALL OUTLINE PACKAGE

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



$\textbf{PowerPAD}^{^{\text{\tiny{TM}}}}\,\textbf{VSSOP - 1.1 mm max height}$

SMALL OUTLINE PACKAGE



NOTES:

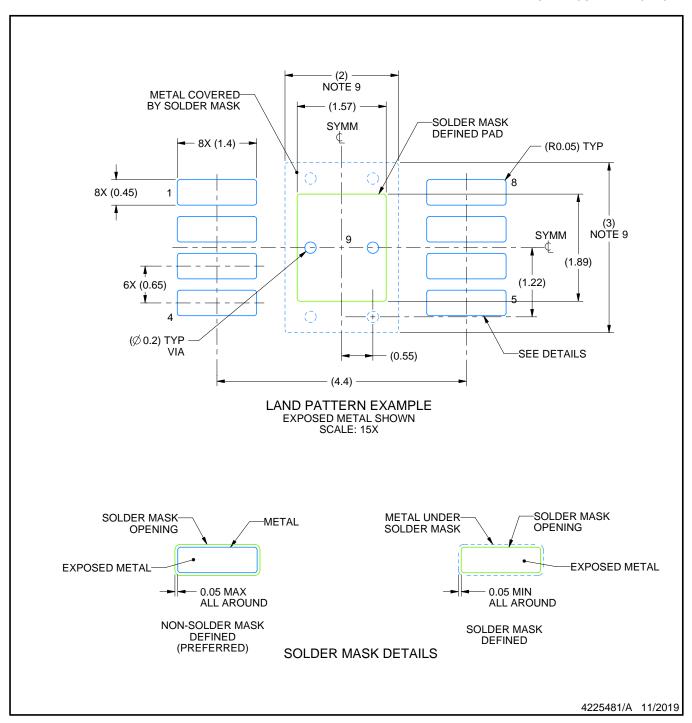
PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

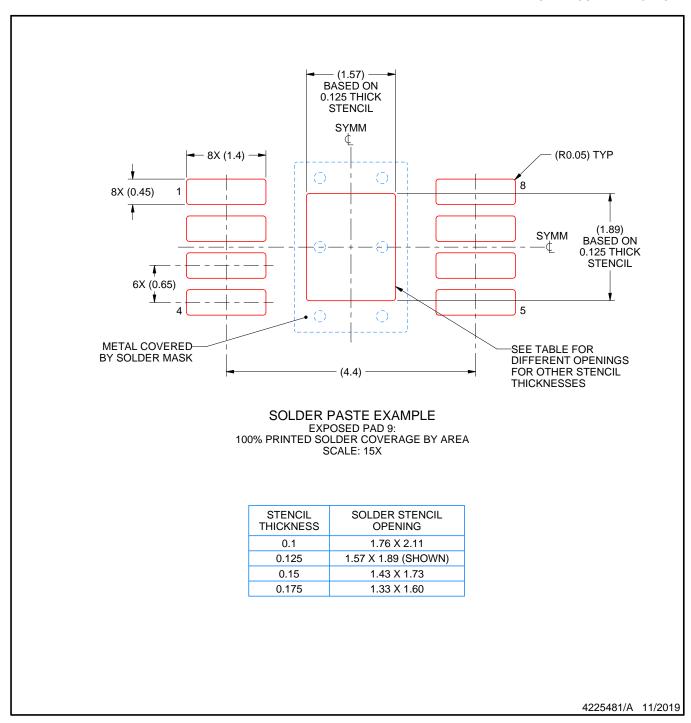
 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-187.





- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
- 9. Size of metal pad may vary due to creepage requirement.



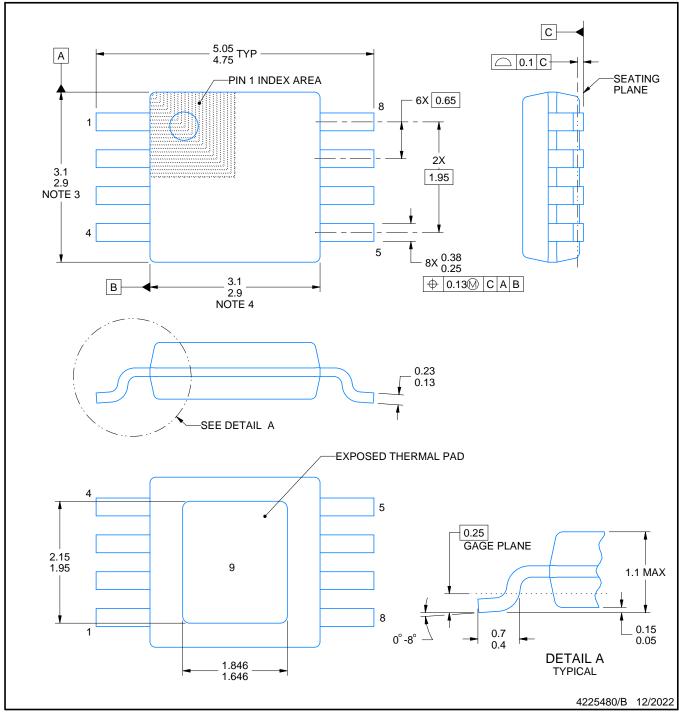


- 10. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 11. Board assembly site may have different recommendations for stencil design.



$\textbf{PowerPAD}^{^{\text{\tiny{TM}}}}\,\textbf{VSSOP - 1.1 mm max height}$

SMALL OUTLINE PACKAGE



NOTES:

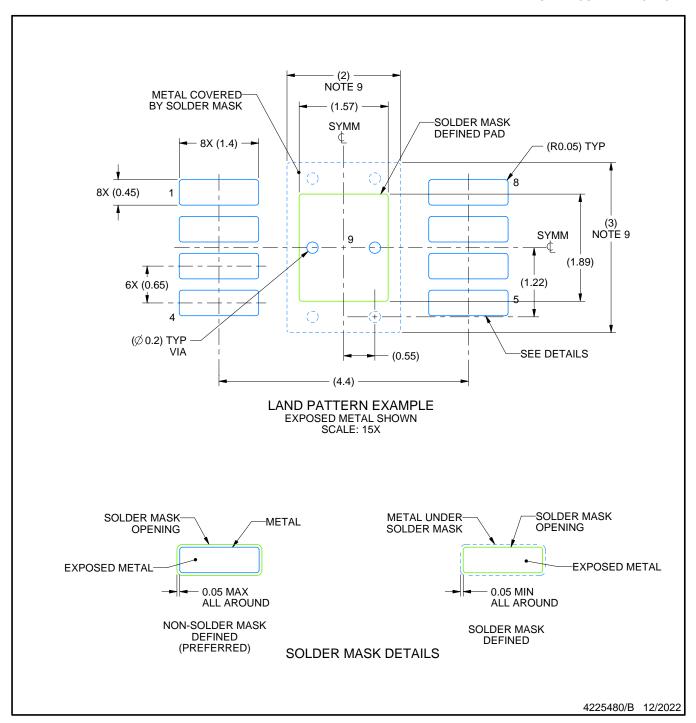
PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

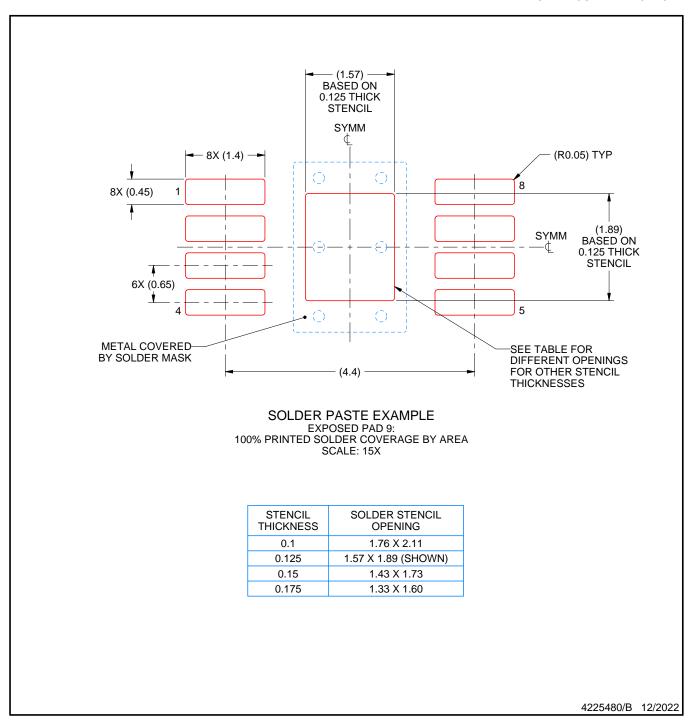
 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-187.





- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
- 9. Size of metal pad may vary due to creepage requirement.





- 10. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 11. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2024, Texas Instruments Incorporated